

TESCAN USA Inc.

Founded in 1991 by a group of managers and engineers from Tesla with its electron microscopy history starting in the 1950's, today TESCAN is a globally renowned supplier of Focused Ion Beam workstations, Scanning Electron Microscopes, and 3D X-ray micro-CT systems. TESCAN's innovative solutions and collaborative nature with its customers have won it a leading position in the world of nano- and microtechnology.

In 2019, TESCAN launched their new Generation 4 series of SEM's and FIB-SEM's to the global marketplace. The state-of-the-art systems provide the most advanced capabilities and quality performance for sample preparation.

TESCAN USA Inc. is the North American arm of TESCAN ORSAY HOLDING, a multinational company established by the merger of Czech company TESCAN, a leading global supplier of SEM's and Focused Ion Beam workstations, and French company Orsay Physics, a world leader in customized Focused Ion Beam and Electron Beam technology.

SEM, FIB-SEM and micro-CT solutions:

- **TESCANMAGNA** – Triglav™ UHRSEM with TriLens™ immersion optics for characterization of nanomaterials
- **TESCAN SOLARIS** – Triglav™ An ultimate resolution FIB-SEM workbench for advanced nanofabrication applications
- **TESCAN SOLARIS X** – Triglav™ A Plasma FIB-SEM platform for deep sectioning and the highest resolution end-pointing for package level failure analysis
- **TESCAN CLARA** – BrightBeam™ Field-free analytical UHR-SEM for materials characterization at the nanoscale
- **TESCAN AMBER** – BrightBeam™ A field-free UHR-SEM combined with the most precise FIB for sample preparation, sub-surface and 3D analysis capabilities to take your materials nanocharacterization further
- **TESCAN AMBER X** – BrightBeam™ A unique combination of Plasma FIB and field-free UHR SEM for the widest range of multiscale materials characterization applications
- **CoreTOM** - a multi-resolution 3D X-ray microscope optimized for high resolution, large field of view imaging of full cores down to microplugs
- **DynaTOM** - a unique and first of its kind dedicated system for fast dynamic *in situ* imaging.
- **UniTOM XL** - enables high-throughput non-destructive 3D imaging for materials research, failure analysis and quality assurance

The company is focused on research, development and the manufacturing of equipment for the following:

- Scanning electron microscopes and ion beam stations
- Ion beam technology
- X-ray micro-CT systems
- Special vacuum chambers and custom systems
- Supplementary accessories for SEM's
- Scientific software compatible with Windows upgrades



How to find us

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